

FDS7079ZN3

30 Volt P-Channel PowerTrench® MOSFET

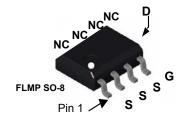
General Description

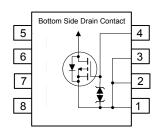
Advanced P Channel MOSFET combined with Advanced SO8 FLMP package providing a device with extremely low thermal impedance and improved electrical performance.

Applications for this device include multi-cell battery protection and charging, including protection and load switching in notebook computer and notebook battery packs.

Features

- -16 A, -30 V. $R_{DS(ON)}$ = 7.5 m Ω @ V_{GS} = -10 V $R_{DS(ON)}$ = 11.5 m Ω @ V_{GS} = -4.5 V
- ESD protection diode (note 3)
- ESD rating: 4kV
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- FLMP SO-8 package for enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		±25	V
I _D	Drain Current - Continuous	(Note 1a)	–16	A
	Pulsed		-60	
P _D	Power Dissipation for Single Operation	(Note 1a)	3.13	W
		(Note 1b)	1.5	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7079ZN3	FDS7079ZN3	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	-			•	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = -250 \mu\text{A}$	-30			V
<u>ΔBV_{DSS}</u> ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		-20		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μА
I _{GSS}	Gate-Body Leakage	V _{GS} = ±25 V, V _{DS} = 0 V			±10	μА
On Chara	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = -250 \mu A$	– 1	-1.5	-3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		0.5		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -10 \text{ V}, I_D = -16 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -13 \text{ A}$ $V_{GS} = -10 \text{ V}, I_D = -16 \text{ A}, T_J = 125 ^{\circ}\text{C}$		6.7 9.4 9.2	7.5 11.5	mΩ
g FS	Forward Transconductance	V _{DS} = -10 V, I _D = -16 A		47		S
Dynamic	Characteristics	•			•	
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$		3630		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		985		pF
C _{rss}	Reverse Transfer Capacitance			490		pF
R_G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		3.0		Ω
Switchin	g Characteristics (Note 2)					•
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -15 \text{ V}, I_{D} = -1 \text{ A},$		10	19	ns
t _r	Turn–On Rise Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$		20	35	ns
$t_{d(off)}$	Turn-Off Delay Time			64	102	ns
t _f	Turn–Off Fall Time			98	157	ns
Q_g	Total Gate Charge	$V_{DS} = -15 \text{ V}, I_{D} = -16 \text{ A},$		39	55	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -5 V		10		nC
Q_{gd}	Gate-Drain Charge			15		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	_			-2.5	Α
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.5 \text{ A} \text{(Note 2)}$		-0.7	-1.2	V
t _{RR}	Reverse Recovery Time	I _F = -16 A,		38		ns
Q _{RR}	Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$ (Note 2)		24		nC

1. $R_{\theta,JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper



85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

- **2.** Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics

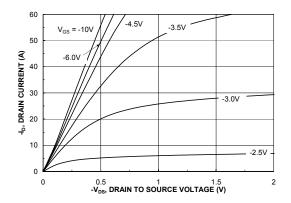
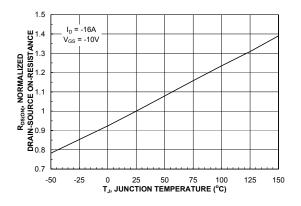


Figure 1. On-Region Characteristics.



igure 3. On-Resistance Variation with Temperature.

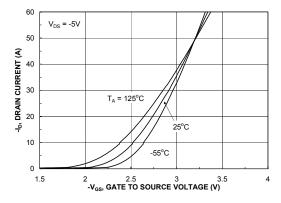


Figure 5. Transfer Characteristics.

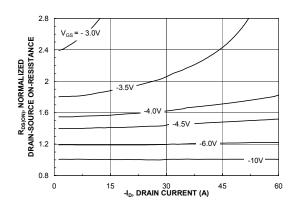


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

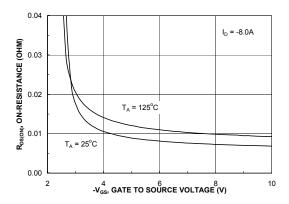


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

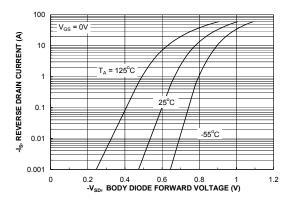
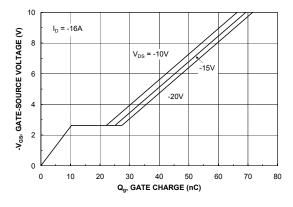


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



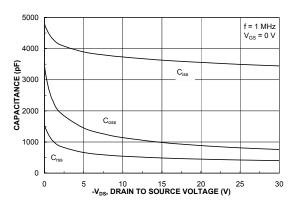
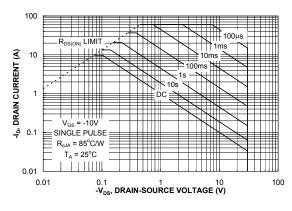


Figure 7. Gate Charge Characteristics.





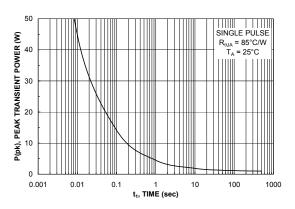


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

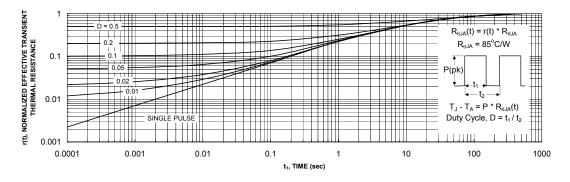
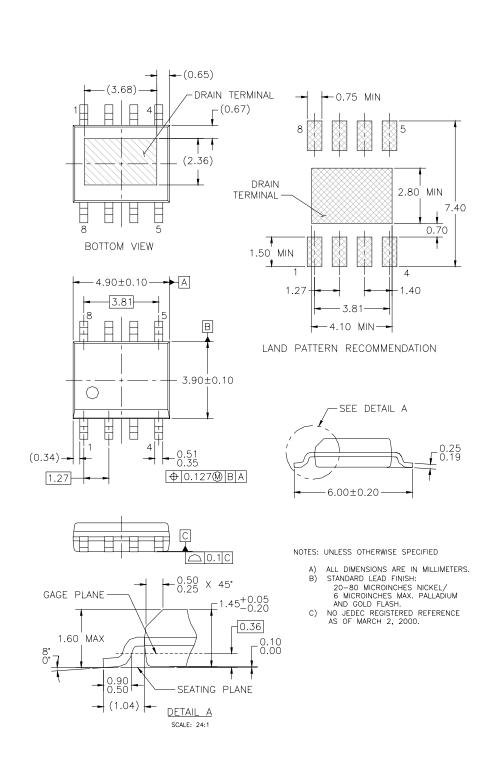


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Dimensional Outline and Pad Layout



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